

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/516,377 KAWAZOE ET AL.	
		Examiner Paul E. Patton	Art Unit 2822	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,670,649 B2	12-2003	Yi et al.	257/109
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Grima-Gallardo et al., "A Comparative Study of (Cu-III-Se2)x-(FeSe)1-x Alloys (III: Al, Ga, In) (0 ≤ x ≤ !) by X-Ray Diffraction, Differential Thermal Analysis and Scanning Electron Microscopy" Phys. Stat. Sol., 187, No 2, 395-405, Wiley, 2001. /
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.